

# **AO4414A**

# **N-Channel Enhancement Mode Field Effect Transistor**



# **General Description**

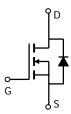
The AO4414A uses advanced trench technology to provide excellent  $R_{\rm DS(ON)}$  and low gate charge. This device is suitable for use as a load switch or in PWM applications. The source leads are separated to allow a Kelvin connection to the source, which may be used to bypass the source inductance. Standard Product AO4414A is Pb-free (meets ROHS & Sony 259 specifications). AO4414AL is a Green Product ordering option. AO4414A and AO4414AL are electrically identical.

#### **Features**

$$\begin{split} &V_{DS}\left(V\right) = 30V \\ &I_{D} = 8.5A \;\; (V_{GS} = 10V) \\ &R_{DS(ON)} < 26m\Omega \; (V_{GS} = 10V) \\ &R_{DS(ON)} < 40m\Omega \; (V_{GS} = 4.5V) \end{split}$$







Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted									
Parameter		Symbol	Maximum	Units					
Drain-Source Voltage		V <sub>DS</sub>	30	V					
Gate-Source Voltage		$V_{GS}$	±20	V					
Continuous Drain	T <sub>A</sub> =25°C		8.5						
Current <sup>A</sup>	T <sub>A</sub> =70°C	I <sub>D</sub>	7.1	Α					
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	50						
	T <sub>A</sub> =25°C	В	3	W					
Power Dissipation	T <sub>A</sub> =70°C	$-P_{D}$	2.1	VV					
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C					

Thermal Characteristics									
Parameter	Symbol	Тур	Max	Units					
Maximum Junction-to-Ambient A	t ≤ 10s	Ь	34	40	°C/W				
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	$R_{\thetaJA}$	62	75	°C/W				
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	18	24	°C/W				

## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	eter Conditions		Тур	Max	Units			
STATIC PARAMETERS									
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V		0.004	1	μА			
		T <sub>J</sub> =55°	С		5	μΛ			
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ = ±20V			100	nA			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_D=250\mu A$	1	1.8	3	V			
$I_{D(ON)}$	On state drain current	$V_{GS}$ =4.5V, $V_{DS}$ =5V	20			Α			
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =8.5A		17	26	mΩ			
		T <sub>J</sub> =125°	С	24	30	11122			
		$V_{GS}$ =4.5V, $I_D$ =5A		27	40	mΩ			
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =5V, $I_{D}$ =8.5A	10	24		S			
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V		0.77	1	V			
Is	Maximum Body-Diode Continuous Curre			4.3	Α				
DYNAMIC	PARAMETERS								
C <sub>iss</sub>	Input Capacitance			621	820	pF			
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =15V, f=1MHz		118		pF			
C <sub>rss</sub>	Reverse Transfer Capacitance			85		pF			
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		0.8	1.5	Ω			
SWITCHII	NG PARAMETERS								
Q <sub>g</sub> (10V)	Total Gate Charge			11.3	17	nC			
Q <sub>g</sub> (4.5V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =8.5A		5.7	8	nC			
$Q_{gs}$	Gate Source Charge	V <sub>GS</sub> -10V, V <sub>DS</sub> -13V, I <sub>D</sub> -6.3A		2.1		nC			
$Q_{gd}$	Gate Drain Charge			3		nC			
t <sub>D(on)</sub>	Turn-On DelayTime			4.5	6.5	ns			
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_{L}$ =1.8 $\Omega$ ,		3.1	5	ns			
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}$ =3 $\Omega$		15.1	23	ns			
t <sub>f</sub>	Turn-Off Fall Time			2.7	5	ns			
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =8.5A, dI/dt=100A/μs		15.5	21	ns			
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	rge I <sub>F</sub> =8.5A, dI/dt=100A/μs		7.1	10	nC			

A: The value of  $R_{0JA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t  $\leq$  10s thermal resistance rating.

Rev 0: December 2005

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

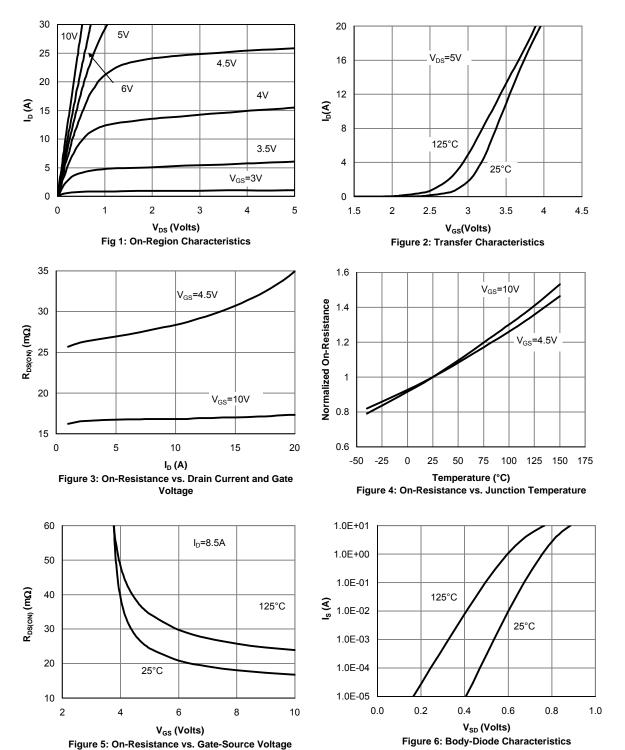
B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using  $80\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The SOA curve provides a single pulse rating.

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

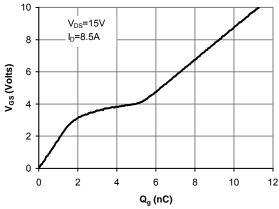


Figure 7: Gate-Charge Characteristics

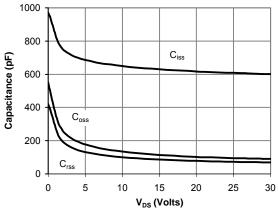


Figure 8: Capacitance Characteristics

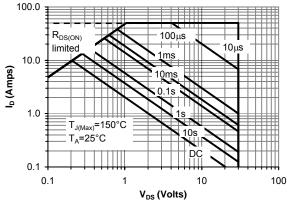


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

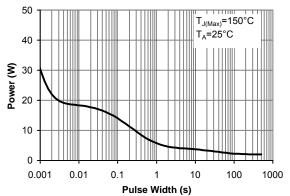


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

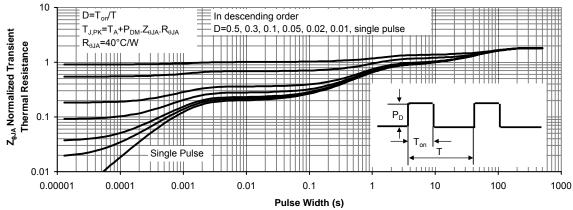


Figure 11: Normalized Maximum Transient Thermal Impedance